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RULE				

APPLICANTS

Mamoru Nakasugi, Kanagawa, JAPAN;
Nobuharu Noji, Kanagawa, JAPAN;
Tohru Satake, Kanagawa, JAPAN;
Masahiro Hatakeyama, Kanagawa, JAPAN;
Toshifumi Kimba, Kanagawa, JAPAN;
Hirosi Sobukawa, Kanagawa, JAPAN;
Shoji Yoshikawa, Tokyo, JAPAN;
Takeshi Murakami, Tokyo, JAPAN;
Kenji Watanabe, Kanagawa, JAPAN;
Tsutomu Kariwata, Kanagawa, JAPAN;
Shin Oowada, Kanagawa, JAPAN;
Mutsumi Saito, Kanagawa, JAPAN;
Yuichiro Yamazaki, Tokyo, JAPAN;
Takamitsu Nagai, Kanagawa, JAPAN;
Ichirota Nagahama, Kanagawa, JAPAN;

* CONTINUING DATA *none*

* FOREIGN APPLICATIONS

JAPAN 2000-193104 06/27/2000
JAPAN 2000-229101 07/28/2000
JAPAN 2000-335934 11/02/2000
JAPAN 2001-11218 01/18/2001
JAPAN 2001-31901 02/08/2001
JAPAN 2001-31908 02/08/2001
JAPAN 2001-33599 02/09/2001
JAPAN 2001-35089 02/13/2001
JAPAN 2001-158662 05/28/2001
JAPAN 2001-162041 05/30/2001
JAPAN 2001-189304 06/22/2001

IF REQUIRED, FOREIGN FILING LICENSE GRANTED
08/28/2001

Foreign Priority claimed	<input checked="" type="checkbox"/> yes <input type="checkbox"/> no	STATE OR COUNTRY	SHEETS DRAWING	TOTAL CLAIMS	INDEPENDENT CLAIMS
35 USC 119 (a)-(d) conditions met	<input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> not other	JAPAN	50	60	13
Method and Acknowledged	<i>Paul Brown</i>	Signature			

ADDRESS
23850

TITLE

Inspection system by charged particle beam and method of manufacturing devices using the system

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